TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (π–MOSV)

2SK2598

Chopper Regulator, DC-DC Converter and Motor Drive Applications

 $\begin{array}{ll} \bullet & Low \ drain-source \ ON \ resistance & : \ RDS \ (ON) = 0.18 \ \Omega \ (typ.) \\ \bullet & High \ forward \ transfer \ admittance & : \ |Y_{fs}| = 13 \ S \ (typ.) \\ \bullet & Low \ leakage \ current & : \ IDSS = 100 \ \mu A \ (max) \ (VDS = 250 \ V) \\ \bullet & Enhancement \ mode & : \ V_{th} = 1.5 \ \sim 3.5 \ V \ (VDS = 10 \ V, \ ID = 1 \ mA) \\ \end{array}$

Absolute Maximum Ratings (Ta = 25°C)

Characteris	stics	Symbol	Rating	Unit	
Drain-source voltage		V_{DSS}	250	V	
Drain-gate voltage (Ro	_{GS} = 20 kΩ)	V_{DGR}	250	V	
Gate-source voltage		V _{GSS}	±20	V	
Drain current	DC (Note 1)	I _D	13	Α	
	Pulse (Note 1)	I _{DP}	52		
Drain power dissipation	n (Tc = 25°C)	PD	60	W	
Single pulse avalanche	e energy (Note 2)	E _{AS}	148	mJ	
Avalanche current		I _{AR}	13	А	
Repetitive avalanche energy (Note 3)		E _{AR}	6	mJ	
Channel temperature		T _{ch}	150	°C	
Storage temperature range		T _{stg}	-55~150	°C	

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Thermal Characteristics

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R _{th (ch-c)}	2.08	°C/W
Thermal resistance, channel to ambient	R _{th (ch-a)}	83.3	°C/W

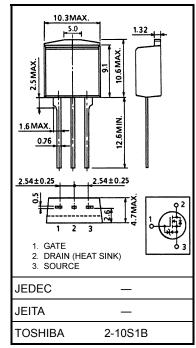
Note 1: Ensure that the channel temperature does not exceed 150°C.

Note 2: V_{DD} = 50 V, T_{ch} = 25°C (initial), L = 1.48 mH, R_G = 25 Ω , I_{AR} = 13 A

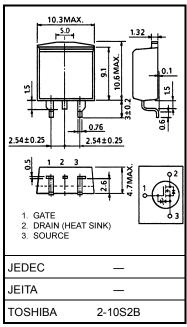
Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device. Please handle with caution.

Unit: mm



Weight: 1.5 g (typ.)



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Electrical Characteristics (Ta = 25°C)

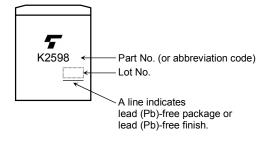
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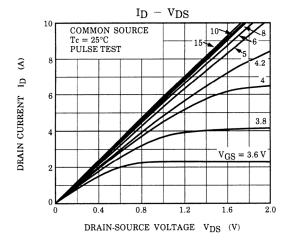
Charac	teristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	rrent	I _{GSS}	V _{GS} = ±16 V, V _{DS} = 0 V	_	_	±10	μΑ
Drain cut-off cur	rent	I _{DSS}	V _{DS} = 250 V, V _{GS} = 0 V		_	100	μΑ
Drain-source br	eakdown voltage	V (BR) DSS	I _D = 10 mA, V _{GS} = 0 V	200	_	_	V
Gate threshold v	roltage	V _{th}	V _{DS} = 10 V, I _D = 1 mA	1.5	_	3.5	V
Drain-source Ol	N resistance	R _{DS (ON)}	V _{GS} = 10 V, I _D = 6.5 A		0.18	0.25	Ω
Forward transfer	admittance	Y _{fs}	V _{DS} = 10 V, I _D = 6.5 A	6	13	_	S
Input capacitano	е	C _{iss}			1800	_	
Reverse transfer	capacitance	C _{rss}	V _{DS} = 10 V, V _{GS} = 0 V, f = 1 MHz	_	130	_	pF
Output capacitar	nce	Coss	ļ		500	_	
Tu Switching time Fa	Rise time	t _r	$V_{GS} = 0 \text{ V}$ $V_{GS} = 0 \text{ V}$ $V_{DD} = 130 \text{ V}$	_	15	_	
	Turn-on time	t _{on}		_	25	-	ns
	Fall time	t _f		l	10	l	TIS
	Turn-off time	t _{off}	Duty $\leq 1\%$, $t_{\rm W} = 10 \mu \rm s$	-	70	-	
Total gate charg plus gate-drain)		Qg		_	40	_	
Gate-source charge		Q _{gs}	$V_{DD} \approx 200 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 13 \text{ A}$		25	_	nC
Gate-drain ("mil	Gate-drain ("miller") charge Q _{gd}		_	15	_		

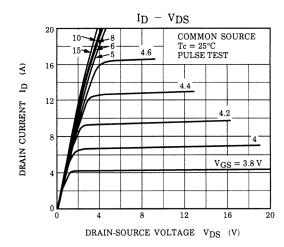
Source-Drain Ratings and Characteristics (Ta = 25°C)

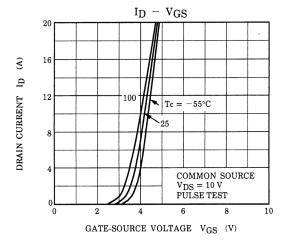
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I _{DR}	_	_	_	13	Α
Pulse drain reverse current (Note 1)	I _{DRP}	_	_	_	52	Α
Forward voltage (diode)	V _{DSF}	I _{DR} = 13 A, V _{GS} = 0 V	_	_	-2.0	V
Reverse recovery time	t _{rr}	I _{DR} = 13 A, V _{GS} = 0 V	1	260	_	ns
Reverse recovery charge	Qrr	dl _{DR} / dt = 100 A / μs	_	0.3	_	μC

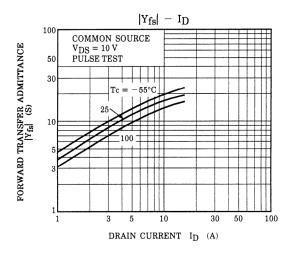
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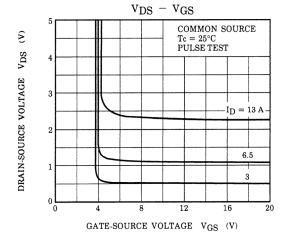


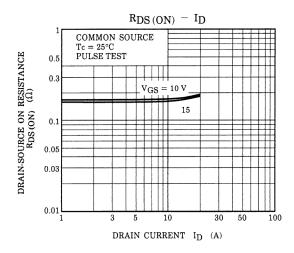


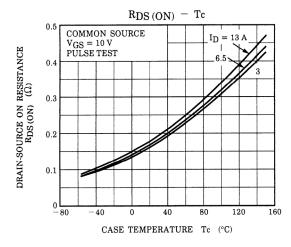


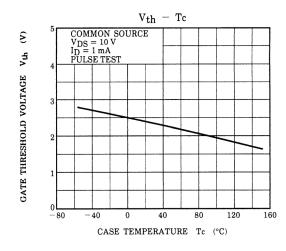


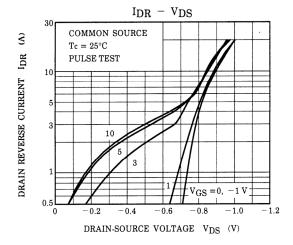


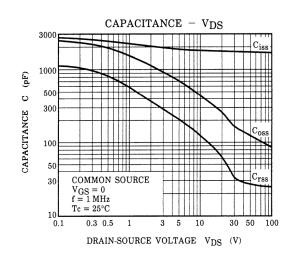


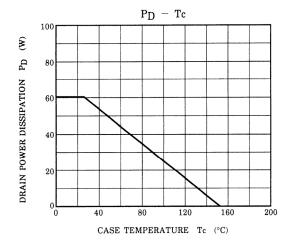


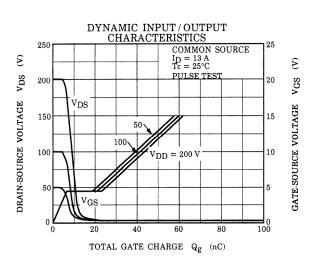




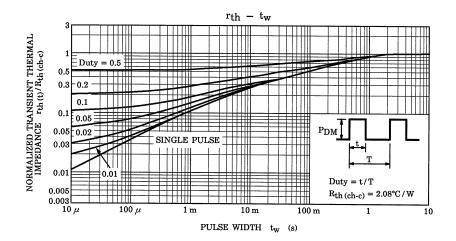


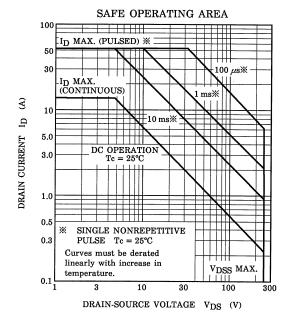


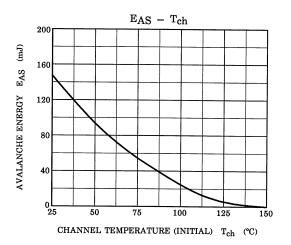


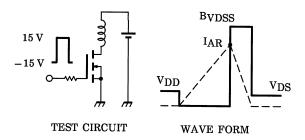


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$$\begin{aligned} &RG = 25~\Omega \\ &V_{DD} = 50~V,~L = 1.48~mH \end{aligned} \qquad EAS = \frac{1}{2} \cdot L \cdot I^2 \cdot \left(\frac{BVDSS}{BVDSS - VDD} \right) \end{aligned}$$

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